Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/611,611	DEHNE ET AL.
Examiner	Art Unit
Mark A. Deuble	3651

SEARCHED				
Class	Subclass	Date	Examiner	
198	463.1			
104	287			
104	288			
213	76			
180	14.1			
29	791			
	799	12/20/2005		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	J				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
see EAST search notes	12/20/2005	MD		